

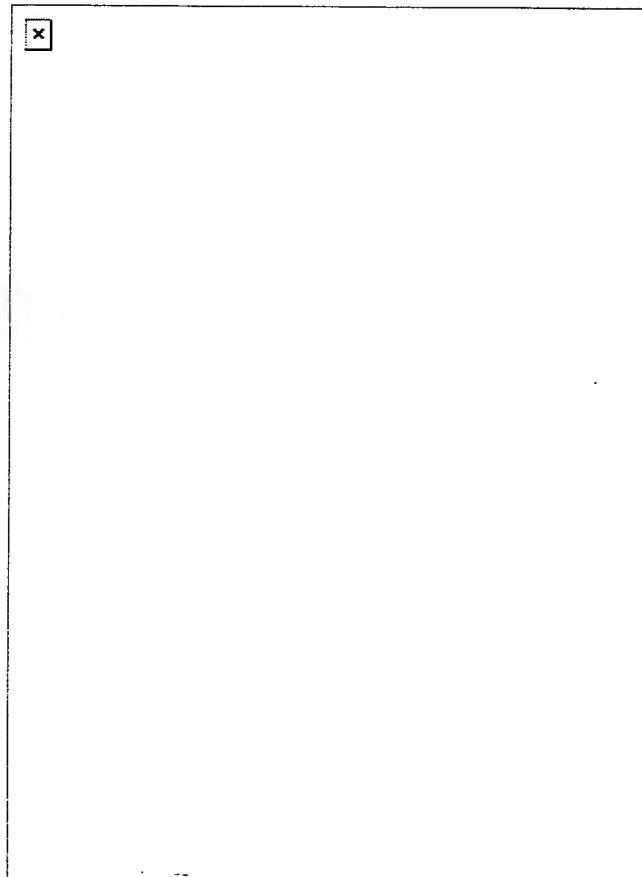
## X-RAY DETECTION CIRCUIT IN SEMICONDUCTOR INTEGRATED CIRCUIT DESIGNING

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**Inventor:** MORIYA ATSUSHI; others: 01  
**Applicant:** HITACHI MEDICAL CORP  
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### Abstract of JP63180884

**PURPOSE:** To achieve a higher quality of picture of a CT image with a high accuracy of data obtained, by surrounding a signal input pad into which a signal is inputted from an X-ray detector and a signal wiring pattern to an input terminal of an amplification circuit therefrom with a ground wiring pattern.

**CONSTITUTION:** Conductive parts (a signal input bonding pad 34 and signal wiring pattern 35) to an input terminal of an amplification circuit with a high impedance from a signal input part from an X-ray detector are surrounded with a ground wiring pattern 37 with a low impedance. This portion shields the inflow of an ohmic current and diffusion current to the conductive parts. This eliminates mixture of these currents with signal currents, thereby providing a highly accurate data.



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